

Dynamics of epitaxial quantum dot laser on silicon subject to chip-scale back-reflection for isolator-free photonics integrated circuits

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Silicon-based epitaxial quantum dot (QD) lasers with strong tolerance for back-reflections have paved the way for developing isolator-free photonics integrated circuits (PICs). This remarkable feature is attributed to the peculiar benefits of QDs, including a large material gain, a strong damping, and a small linewidth enhancement factor [1]. The laser performance can also be optimized by applying p-modulation doping in the active region [1]. In a previous study, the sensitivity of epitaxial QD lasers on silicon subject to short- and long-delay optical feedback were performed [2]. On the top of that, a further investigation of the feedback dynamics on the intra- and inter-chip scale is of significant importance for photonic integration applications.

This paper reports on a study on the pulsation dynamics of a 1.3 μm Si-based p-doped epitaxial QD laser under strong optical feedback both in short-cavity regime (SCR) and long-cavity regime (LCR). More details of the laser studied can be found elsewhere [2]. In this study, the SCR and LCR is defined as the ratio of f_{RO}/f_{ext} being <1 or >1 , respectively, with f_{RO} the relaxation oscillation frequency of the solitary laser and $f_{ext} = c/2L_{ext}$ the external cavity frequency [3]. The feedback strength r_{ext} is defined as the ratio of the reflected power to the laser output power. By increasing r_{ext} to $\sim 70\%$ (~ -1.55 dB), these results confirm that the QD devices operating at $4.4 \times I_{th}$ under 30°C exhibit strong tolerance for back-reflections and do not emit chaotic oscillations. This is confirmed by tracking the full transition from SCR to LCR through the increase of the external cavity length L_{ext} from 4 to 50 cm. Fig.1(a) and (b) depict the pulsation states and corresponding oscillation frequencies of the laser under different feedback conditions, respectively. The vertical red dashed lines correspond to the condition $f_{RO}/f_{ext} = 1$ hence indicating the frontier between the SCR and LCR. By increasing r_{ext} in LCR, the laser system firstly enters into a quasi period-one (Q1, black) oscillation state in which the oscillation frequency coincides with f_{ext} (black curve shown in Fig. 1(b)). Further increasing r_{ext} , the self-pulsation frequency f_{sp} (yellow curve shown in Fig. 1(b)) approximates f_{RO} (black dashed line in Fig. 1(b)) is excited while f_{ext} still exists, hence the laser enters into quasi-periodic (QP, grey) oscillation state. Shortening the L_{ext} into SCR, the laser oscillating at f_{ext} exhibits a period-one (P1, red) oscillation. Then, the regular pulse package (RPP, yellow) dynamics takes place for $f_{RO}/f_{ext} < 0.5$. To sum, the QD laser remains in the solitary state (S) up to r_{ext} of 45% in the SCR. In this regime, the increase of the r_{ext} associated with the onset of pulsation dynamics with decreasing L_{ext} suggests that these devices are highly reflection-resistant on the scale of PICs.

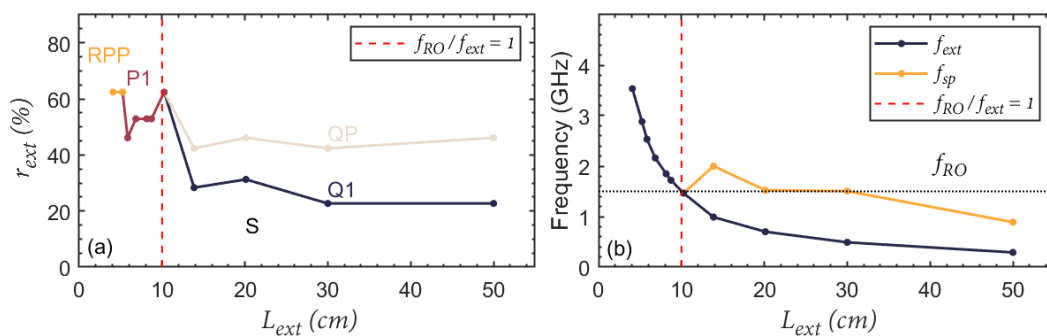


Fig. 1 (a) Mapping of the dynamical states under different feedback conditions, and (b) the oscillation frequency f_{sp} (yellow) and f_{ext} (black) as a function of L_{ext} . The p-doped QD laser operates at $4.4 \times I_{th}$ under 30°C .

To conclude, the observed high tolerance for chip-scale back-reflection points out the potential of epitaxial QD lasers on silicon as ultra-stable light sources applying to isolator-free PICs. The analysis of the pulsing dynamics is also strongly driven by the growing interest in the integrated microwave photonic technology.

References

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